

Notice of References Cited	Application/Control No. 10/051,230	Applicant(s)/Patent Under Reexamination KAWAMURA ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
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X	B	US-006187492B	02-2001	Ri et al.	430	96
X	C	US-005336582A	08-1994	Takegawa et al.	430	58.7
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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